

Search Notes 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/708,489	CHANG ET AL.	
				Examiner	Art Unit	
				Y. J. Han	2838	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
323	312					
	313					
	314					
	274					
	275					
	276					
	277					
	280					
	281					
327	530					
	534					
	535					
Search	updated	6/1/2006	/JH/			
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			